MOSFET - Power, Single **N-Channel, DFNW8**

150 V, 6.4 mΩ, 128 A

NVMTS6D0N15MC

Features

- Small Footprint (8x8 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Symbol	Parameter			Value	Unit
V _{DSS}	Drain-to-Source Voltage			150	V
V _{GS}	Gate-to-Source Voltage			±20	V
I _D	Continuous Drain Current R _{θJC} (Note 2)	Steady State	T _C = 25°C	128	Α
P _D	Power Dissipation R _{θJC} (Note 2)			237	W
I _D	Continuous Drain Current R _{θJC} (Note 2)	Steady State	T _C = 100°C	90	Α
P _D	Power Dissipation $R_{\theta JC}$ (Note 2)			119	W
I _D	Continuous Drain Current $R_{\theta JA}$ (Notes 1, 2)	Steady State	T _A = 25°C	18	Α
P _D	Power Dissipation R _{θJA} (Notes 1, 2)			5	W
I _D	Continuous Drain Current $R_{\theta JA}$ (Notes 1, 2)	Steady State	T _A = 100°C	13	А
P _D	Power Dissipation R _{θJA} (Notes 1, 2)			2.4	W
I _{DM}	Pulsed Drain Current	$T_A = 25^{\circ}C$	C, t _p = 10 μs	900	Α
T _J , T _{stg}	Operating Junction and Storage Temperature Range			-55 to 175	°C
I _S	Source Current (Body Diode)			198	Α
E _{AS}	Single Pulse Drain-to-Source Avalanche Energy (I _L = 10.2 A _{pk})			2376	mJ
TL	Lead Temperature Soldering Reflow for Soldering Purposes (1/8" from case for 10 s)			260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

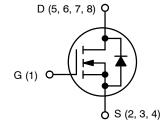
- 1. Surface-mounted on FR4 board using 1 in² pad size, 1 oz Cu pad.
- 2. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted



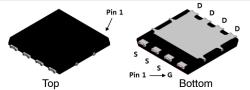
ON Semiconductor®

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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
150 V	6.4 mΩ @ 10 V	128 A



N-CHANNEL MOSFET



DFNW8 8.3x8.4. 2P PQFN88 **CASE 507AP**

MARKING DIAGRAM



6D0N15MC = Specific Device Code

= Assembly Location WL = Wafer Lot Code = Year Code = Work Week Code

ORDERING INFORMATION

Device	Package	Shipping [†]
NVMTS6D0N15MC	DFNW8 PQFN88 (Pb-Free)	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL RESISTANCE RATINGS

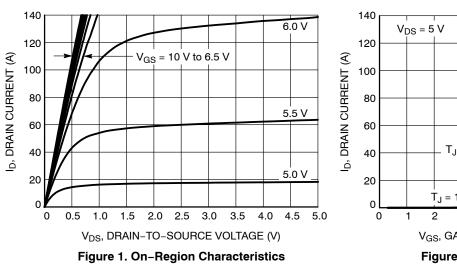
Symbol	Parameter	Max	Unit
$R_{ heta JC}$	Junction-to-Case - Steady State (Note 2)	0.63	°C/W
$R_{ hetaJA}$	Junction-to-Ambient - Steady State (Note 2)	31.6	

Symbol	Parameter	Test Condition		Min	Тур	Max	Unit
OFF CHARACT	ERISTICS				•	•	
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		150	_	_	V
V _{(BR)DSS} / T _J	Drain-to-Source Breakdown Voltage Temperature Coefficient	I _D = 250 μA, ref	I _D = 250 μA, ref to 25°C		58.67	-	mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{GS} = 0 V, V _{DS} = 120 V	$T_{J} = 25^{\circ}C$ $T_{J} = 125^{\circ}C$	-	_	1 10	μA μA
I _{GSS}	Gate-to-Source Leakage Current	V _{DS} = 0 V, V _{GS}	, i	-	_	±100	nΑ
	ERISTICS (Note 3)	100 - 1, 100		1			
V _{GS(TH)}	Gate Threshold Voltage	V _{GS} = V _{DS} , I _D =	= 379 μA	2.5	3.6	4.5	V
V _{GS(TH)} / T _J	Negative Threshold Temperature Coefficient	I _D = 250 μA, ref		_	-9.14	_	mV/°C
R _{DS(on)}	Drain-to-Source On Resistance	V _{GS} = 10 V, I _D :		_	4.6	6.4	mΩ
9FS	Forward Transconductance	V _{DS} = 5 V, I _D =		_	127	_	S
R _G	Gate-Resistance	T _A = 25°C		_	1.1	_	Ω
	APACITANCES	1		1	1		<u> </u>
C _{ISS}	Input Capacitance	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 75V		_	4815	_	pF
C _{OSS}	Output Capacitance			_	1482	_	
C _{RSS}	Reverse Transfer Capacitance			_	9.7	_	
Q _{G(TOT)}	Total Gate Charge	$V_{GS} = 10 \text{ V}, V_{DS} = 75 \text{ V},$ $I_{D} = 69 \text{ A}$ $V_{GS} = 0 \text{ V}, V_{DS} = 75 \text{ V}$		-	58	_	nC
Q _{G(TH)}	Threshold Gate Charge			_	34	_	
Q _{GS}	Gate-to-Source Charge			-	26	_	
Q _{GD}	Gate-to-Drain Charge			_	8	_	
Q _{OSS}	Output Charge			-	173	-	nC
SWITCHING CH	HARACTERISTICS, VGS = 10 V (Note 3)			•			
t _{d(ON)}	Turn-On Delay Time	V _{GS} = 10 V, V _D	_S =75 V,	_	30	-	ns
t _r	Rise Time	$I_D = 69 \text{ A}, R_G =$	6 Ω	-	7	_	1
t _{d(OFF)}	Turn-Off Delay Time			-	38	_	1
t _f	Fall Time			-	6	-	
DRAIN-SOURC	CE DIODE CHARACTERISTICS				•	•	
V _{SD}	Forward Diode Voltage	$V_{GS} = 0 \text{ V},$ $I_{S} = 69 \text{ A}$ $T_{J} = 25^{\circ}\text{C}$ $T_{J} = 125^{\circ}\text{C}$	T _J = 25°C	-	0.87	1.2	V
			-	0.70	-		
t _{RR}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } dI_S/c$	dt = 100 A/μs,	-	72	_	ns
ta	Charge Time	I _S = 69 A		-	49	-	
t _b	Discharge Time			-	23	-	
Q _{RR}	Reverse Recovery Charge			-	125	_	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Switching characteristics are independent of operating junction temperatures

TYPICAL CHARACTERISTICS



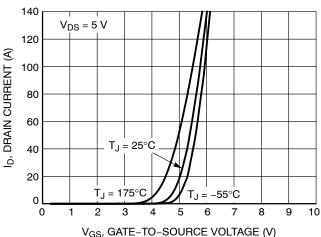


Figure 2. Transfer Characteristics

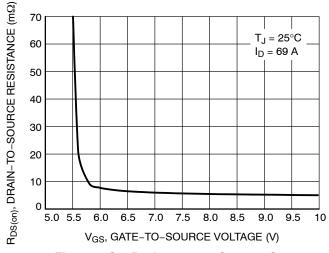


Figure 3. On-Resistance vs. Gate-to-Source Voltage

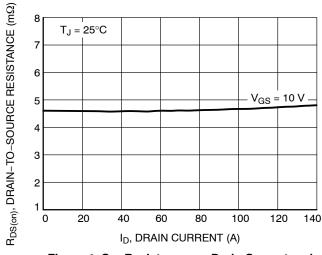


Figure 4. On–Resistance vs. Drain Current and Gate Voltage

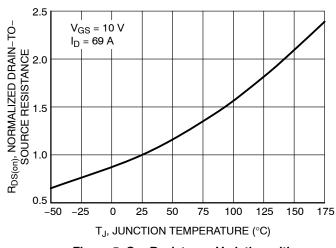


Figure 5. On–Resistance Variation with Temperature

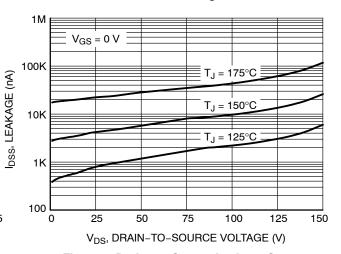
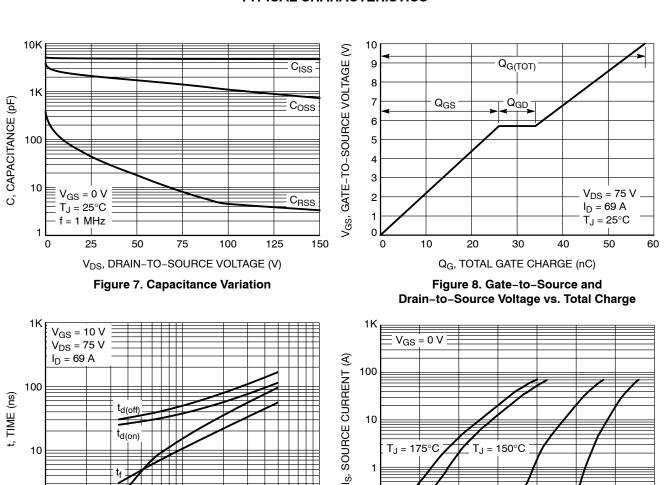


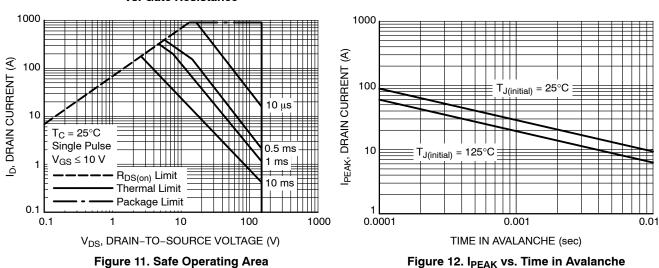
Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS



 $\label{eq:RGG} \textbf{R}_{\textbf{G}}, \, \textbf{GATE RESISTANCE} \; (\Omega)$ Figure 9. Resistive Switching Time Variation vs. Gate Resistance

10



0.1

0.3

0.4

100

 $T_J = 25^{\circ}C$

0.6

V_{SD}, SOURCE-TO-DRAIN VOLTAGE (V)

Figure 10. Diode Forward Voltage vs. Current

0.7

 $T_{.1} = -55^{\circ}C$

0.9

0.8

TYPICAL CHARACTERISTICS

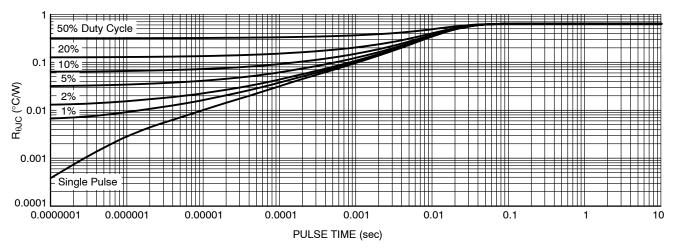
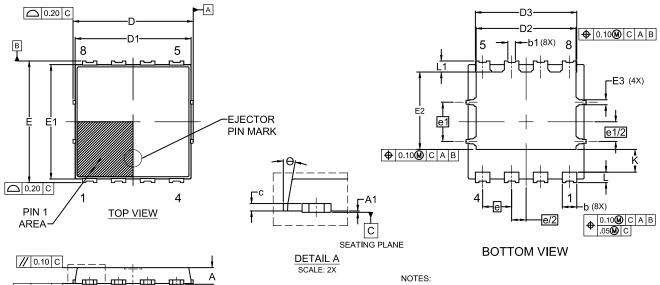


Figure 13. Thermal Characteristics

PACKAGE DIMENSIONS

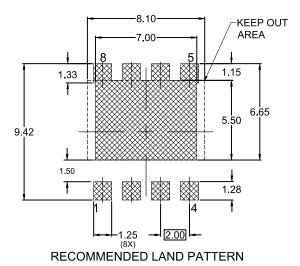
DFNW8 8.3x8.4, 2P CASE 507AP **ISSUE A**

DATE 14 AUG 2018



- 1 -ф 0.10 C L SEE DETAIL A

FRONT VIEW



- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
 CONTROLLING DIMENSION: MILLIMETERS
 COPLANARITY APPLIES TO THE EXPOSED PADS AS WELL AS THE TERMINALS.
- 4. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH,
- 4. DIMENSIONS DI AND ET DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

 5. SEATING PLANE IS DEFINED BY THE TERMINALS.

 "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.

1				
MILLIMETERS				
MIN.	NOM.	MAX.		
1.00	1.10	1.20		
0.00	-	0.05		
0.90	1.00	1.10		
0.43	0.53	0.63		
0.23	0.28	0.33		
8.20	8.30	8.40		
7.90	8.00	8.10		
6.80	6.90	7.00		
6.90	7.00	7.10		
8.30	8.40	8.50		
7.80	7.90	8.00		
5.24	5.34	5.44		
0.25	0.35	0.45		
2.00 BSC				
1.00 BSC				
2.70 BSC				
1.35 BSC				
1.50	1.57	1.70		
0.64	0.74	0.84		
0.67	0.77	0.87		
0°		12°		
	MIN. 1.00 0.00 0.90 0.43 0.23 8.20 7.90 6.80 6.90 8.30 7.80 5.24 0.25	MIN. NOM. 1.00 1.10 0.00 0.90 1.00 0.43 0.53 0.23 0.28 8.20 8.30 7.90 8.00 6.80 6.90 7.00 8.30 8.40 7.80 7.90 5.24 5.34 0.25 0.35 2.00 BS 1.00 BS 2.70 BS 1.35 BS 1.50 1.57 0.64 0.74		

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